56 🛛 CLK

55 D1

54 D2

53 D3

52 🛛 D4

50 D5

49 D6

48 D7

46 D8

45 🛛 D9

44 D10

43 VCC

42 🛛 V_{REF}

40 D11 39 D12

38 D13

37 GND

36 D14

35 D15

34 **D**16

33 GND

32 D17

31 **I** D18

30 D19

29 D20

41 OE

47 GND

51 GND

SN54GTL16921 ... WD PACKAGE SN74GTL16921 ... DGG OR DL PACKAGE (TOP VIEW)

> Q1 [1

Q2 🛛 2

GND 🛛 3

Q3 🛛 4

Q4

Q5 🛛 7

Q6 🛛 8

Q7 🛛 9

Q9 12 Q10 13

V_{CC} [] 14

GND 15

Q11 16

Q12 17

Q13 18

GND 🛛 19

Q14 20

Q15 21

Q16 22

GND 23

Q17 24

Q18 25

GND 26

Q19 27

Q20 28

GND 10

Q8 [

5 GND 6

11

•	<i>EPIC-</i> II <i>B</i> ™ (Enhanced-Performance
	Implanted C	CMOS) Submicron Process

- Members of the Texas Instruments Widebus™ Family
- Provide GTL Signals Levels on Both Inputs and Outputs
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages, and Ceramic Flat (WD) Package

description

The 'GTL16921 have 20 single-bit flip-flops, which are designed to provide terminated GTL logic levels.

These devices can be used as one 20-bit flip-flop. The 20 flip-flops are edge-triggered D-type flip-flops. The 'GTL16921 provide true data at the Q outputs on the positive transition of the clock (CLK) input.

The output-enable (OE) input can be used to place the outputs in a high state. The outputenable input does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54GTL16921 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74GTL16921 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE
(each flip-flop)

(each hip-hop)							
	INPUTS	OUTPUT					
OE	CLK	Q					
L	\uparrow	Н	Н				
L	\uparrow	L	L				
L	L	Х	Q ₀ Z				
н	Х	Х	Z				



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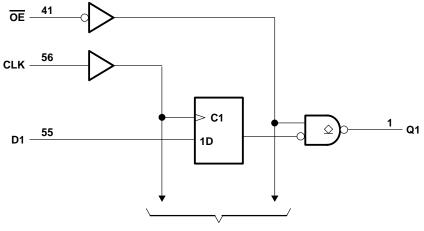
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SN54GTL16921, SN74GTL16921 20-BIT FLIP-FLOPS WITH GTL I/O LEVELS

SCBS313C - JULY 1993 - REVISED JULY 1995

logic diagram (positive logic)



To 19 Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	–0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	
Current into any output in the low state, I _O	80 mA
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I_{OK} (V _O < 0 or V _O > 0)	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2): DGG package	1 W
DL package	1.4 W
Storage temperature range, T _{stg}	−65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.



recommended operating conditions

		SN54GTL16921			SN7	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	3		3.6	3		3.6	V
VREF	Supply voltage	0.74	0.8	0.87	0.74	0.8	0.87	V
VI	Input voltage	0		VCC	0		VCC	V
∨он	High-level output voltage			3.6			3.6	V
VIH	High-level input voltage	VREF +50 mV			V _{REF} +50 mV			V
VIL	Low-level input voltage		١	/REF – 50 mV		V	REF – 50 mV	V
Iк	Input clamp current			-18			-18	mA
I _{OL}	Low-level output current			40			40	mA
Т _А	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range, $V_{REF} = 0.8 V$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SNS	SN54GTL16921			SN74GTL16921			
				MIN	TYP†	MAX	MIN	түр†	MAX	UNIT	
VIK		V _{CC} = 3 V,	l _l = –18 mA			-1.2			-1.2	V	
VOL		V _{CC} = 3 V,	I _{OL} = 40 mA			0.4			0.4	V	
1.		$\lambda = -2\lambda$	$V_{I} = V_{CC}$			5			5		
1		V _{CC} = 3 V	$V_{I} = 0$			-5			-5	μA	
ЮН		$V_{CC} = 3 V,$	V _{OH} = 3.6 V							μΑ	
	Outputs high	V _{CC} = 3 V,	l _O = 0,							mA	
ICC	Outputs low	$V_I = V_{CC}$ or GND	-							ША	
Ci		Per IEEE1194.0-1991			4			4		pF	
Co		Per IEEE1194.0-1991			6			6		pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

PRODUCT PREVIEW



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